FORM PTO-1449 (Modified)

U.S. Department of Commerce, Patent and Trademark Office

Docket No.

99-102/1D

Serial No.

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

Applicants

Wilbur G. Catabay et al.

Filing Date Herewith Group 2813

	L
	l
<b>-</b>	ŧ
.0	ı
10 D	l
"O' = G	ı
· 0 = 1	ı
	ı
	Į
03	1
	ı
	ı
0	ı
	ł

					Herewith		2813	1
			υ.	S. Patent Documents				
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Da If Appropria	
IAIC	AA	5,874,367	2/23/99	Dobson	438	787	12/28/	<del>2</del> 4
_ 1	AB	5,904,154	5/18/99	Chien et al.	134	1.2	7/24/97	
	AC	5,882,489	3/16/99	Bersin et al.	204	192.35	4/26/96	
	AD	5,858,879	1/12/99	Chao et al.	438	725	6/6/97	
	AE	3,012,861	12/12/61	Ling	23	223.5	1/15/60	
	AF	3,178,392	4/13/65	Kriner	260	46.5	4/9/62	
	AG	3,832,202	8/27/74	Ritchie	106	287	8/8/72	
	AH	3,920,865	11/18/75	Läufer et al.	427	220	4/6/72	
/	AI	4,705,725	11/10/87	Glajch et al.	428	405	11/28/86	
Λ	AJ	5,194,333	3/16/93	Ohnaka et al.	428	405	12/18/90	
W	AK	5,874,745	2/23/99	Kuo	257	59	8/5/97	
			Fore	eign Patent Documents	3			
							Translatio	n
		Document Number	Date	Country	Class	Subclass	Yes	No
MC	AL	DE 198 04 375 Al	7/1/99	Germany	H 01 L	21/312		Х
1	AM	EP 0 706 216 A2	4/10/96	Europe	H 01 L	23/532	N/A	
	AN	EP 0 949 663 A2	10/13/99	Europe	H 01 L	21/312	N/A	
	AO	63003437	1/8/88	Japan	H 01 L	21/90	X-Abstract Only	
VXV	AP	WO 99/41423	8/19/99	PCT	C 23 C		N/A	
	·	OTHER AR	T (Including A	author, Title, Date, Perti	nent Pages,	Etc.)		
Inc	AR	System for	High Perfor	tegration of 0.25 μm T rmance ASIC", <u>1997 Pro</u> ra, CA, June 10-12, 19	ceedings Fo	ourteenth I	nter-connect nternational	VMI
1200	AS	Dobson, C.D.	, et al., " <i>I</i>	Advanced SiO <sub>2</sub> Planariza	tion Using	Silane and	d H <sub>2</sub> O <sub>2</sub> ",	

Examiner

Date Considered

1/23/33

McClatchie, S., et al., "Low Dielectric Constant Oxide Films Deposited Using CVD Techniques", 1998 Proceedings Fourth International DUMIC Conference, February 16-17, 1998, pp. 311-318.

\*EXAMINER: Initial of reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

Semiconductor International, December 1994, pp. 85-88.

FORM PTO-1449 (Modified) Docket No. Serial No. U.S. Department of Commerce, Patent and Trademark Office 99-102/1D INFORMATION DISCLOSURE STATEMENT BY APPLICANT Applicants Wilbur G. Catabay et al. (Use several sheets if necessary) Filing Date Group Herewith 2813 U.S. Patent Documents \*Examiner Document Filing Date Initial Number Date Name Class Subclass Appropriate AΑ 6,066,574 5,23/00 You et al. 438 781 11/6/98 AB 6,051,477 4/18/00 Nam 438 404 10/22/96 AC 6,025,263 2/15/00 Tsai et al. 438 624 9/11/97 AD 5,939,763 8/17/99 Hao et al. 257 411 9/5/96 1/26/99 257 ΑE 5,864,172 Kapoor et al. 634 8/13/96 AF 5,688,724 11/18/97 Yoon et al. 437 235 12/23/94 5,470,801 437 238 6/28/93 AG 11/28/95 Kapoor et al. ΑH 5,364,800 11/15/94 Joyner 437 28 6/24/93 ΑI 4,771,328 9/13/88 Malaviya et al. 357 49 11/24/86 ΑJ 3,652,331 3/28/72 Yamazaki 117 201 3/13/69 AΚ 6,153,524 11/28/00 Henley et al. 438 691 7/28/98 Foreign Patent Documents Translation Class Subclass Yes No Document Date Country Number ALMA AN AO AΡ OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) Peters, Laura, "Pursuing the Perfect Low-k Dielectric", Semiconductor AR International, Vol. 21, No. 10, September, 1998, pp. 64-66, 68, 70, 72, and 74. Koda, Seiichiro, et al., "A Study of Inhibition Effects for Silane AS Combustion by Additive Gases", Combustion and Flame, Vol. 73, No. 2, August, 1988, pp. 187-194. Sugahara, Satoshi, et al., "Chemical Vapor Deposition of CF3-Incorporated Silica Films for Interlayer Dielectric Application", 1999 Joint International Meeting, Electrochemical Society Meeting Abstracts, Vol. 99-2, 1999, Abstract No. 746. Date Considered Examiner \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with

MPEP 609; Draw line through citation if not in conformance and not considered. Include copy

of this form with your communication to applicant.

· 3					şh	ueet <u>3</u>	_ of	<u>4</u> sł	ıeets
FORM PTO-1		•	Datent an	d Trademark Office	Docket No. Serial		al No.		
U.B. Bepar	· Cilicate	OI COMMETCE	, racent an	d Ilademaik Office	99-102/1D				
INFORMATION DISCLOSURE STATEMENT BY APPLICANT						s			
(Use several sheets if necessary)						Catabay	et a	1.	
						ıte	Grou 2813		
			υ.	S. Patent Documents					
*Examiner Initial		Document Number	Date	Name	Class	Subclas	s I	iling Da f ppropria	
MU	AA	6,051,073	4/18/00	Chu et al.	118	723	6	/3/98	
4	AB	5,580,429	12/3/96	Chan et al.	204	192.38	6	/7/95	
	AC	5,558,718	9/24/96	Leung	118	723E	4.	/8/94	
	AD	5,628,871	5/13/97	Shinagawa	438	514	6	/24/94	
	AE	6,028,015	2/22/00	Wang et al.	438	789	3,	/29/99	
	AF	6,114,259	9/5/00	Sukharev et al.	438	789	7,	/27/99	
	AG	6,147,012	11/14/00	Sukharev et al.	438	787	1:	1/12/99	
	AH	6,204,192	3/20/01	Zhao et al.	438	723	3,	/29/99	
	AI	6,232,658	5/15/01	Catabay et al.	257	701	6,	/30/99	
<u> </u>	AJ	6,037,248	3/14/00	Ahn	438	619	6,	/13/97	
boc	AK	5,675,187	10/7/97	Numata et al.	257	758	5,	/16/96	
			Fore	ign Patent Documents	3				
	<u></u>	,					Tra	nslation	1
		Document Number	Date	Country	Class	Subclas	s Ye	es	No
	AL								
	AM								
	AN								
	AO								
	AP								
	0	THER ART (In	cluding Aut	hor, Title, Date, Pe	ertinent Pa	ages, Etc	z.)		
	AR					· · <del></del>			

AS

AT

Examiner

Date Considered

( holo

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

				<del> </del>					
• •,					Sh	neet <u>4</u>	<	of <u>4</u> sheets	
FORM PTO-1					Docket No	o.	Se	erial No.	
U.S. Depar	U.S. Department of Commerce, Patent and Trademark Office								
INFO	RMATIO	ON DISCLOSUR	E STATEMENT	BY APPLICANT	Applicants				
	(Use	e several sh	eets if nece	ssary)	Wilbur G.	Catabay	y et	t al.	
					Filing Da Herewith	ite		roup 313	
			ŭ.s	. Patent Documents					
*Examiner Initial		Document Number	Date	Name	Class	Subclas	ss	Filing Date If Appropriate	
W	AA	5,559,367	9/24/96	Cohen et al.	257	77		7/12/94	
1	AB	5,376,595	12/27/94	Zupancic et al.	501	12		8/28/92	
	AC	6,043,167	3/28/2000	Lee et al.	438	789		10/10/97	
	AD	5,314,845	5/24/94	Lee et al.	437	238		2/2/90	
	AE	5,915,203	6/22/99	Sengupta et al.	438	669		6/10/97	
	AF	6,054,379	4/25/2000	Yau et al.	438	623		2/11/98	
	AG	5,989,998	11/23/99	Sugahara et al.	438	623		8/28/97	
$\overline{V}$	AH	6,215,087	04-2001	Akahori et al.	219	121.43		6/16/198	
LAK	AI	6,303,047	10/16/01	Aronowitz et al.	252/1	106/287.1	13	3/22/99	

## Foreign Patent Documents

106/287.13 3/22/99

Translation Document Date Class Country Subclass Yes No Number ALΑM AN ΑO ΑP

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

ΆR AS AΤ

АJ ΑK

Examine

Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

COPY	OF	PA	ŖΕ	RS
ORIGII				

Sheet	1	of	1	sheets

FORM PTO-1	449 (	Modified)	, •		Docket No	).	Serial No.			
U.S. Depar	tment	of Commerce	, Patent an	d Trademark Office	99-102/10	)	10/099,641			
INFO	INFORMATION DI <u>SC</u> LOSURE STATEMENT BY APPLICANT					Applicants				
	(Use several speets if necessary)					Catabay	et al.			
	7			-	Filing Date Group					
	PA	JUN 0 5 2002 2			March 15,	2002	Unknown			
		RAOGMARK OF S	<b>U</b> .	S. Patent Documents				***		
*Examiner Initial		Document Number	Date	Name	Class	Subclas	Filing Da If Appropria			
	AA						1.2220222			
	AB									
	AC									
	AD									
	AE									
	AF									
	AG							····		
	AH									
	AI		4. 4							
	AJ									
	AK									
			Fore	eign Patent Documents	5					
	r		· · · · · · · · · · · · · · · · · · ·	1		7	Translatio	n T		
		Document Number	Date	Country	Class	Subclas	ss Yes	No		
M	AL	2000-267128	9/29/00	Japan	G02F	1/136	X-Abstract Only			
,	AM							-		
	AN									
	AO							<b>_</b>		
	AP									
	<u> </u>	THER ART (In	ncluding Aut	thor, Title, Date, Pe	ertinent P	ages, Et	c.)			
	AR									
	AS									
	АТ				_					
Examiner	X	AV	Date Cons	idered 1/23/0	3					
*EXAMINER: MPEP 609;	Draw	tial if refe	n citation i	dered, whether or no	ot citation e and not	n is in consider	conformance w ed. Include			